

Conference Paper

Capacitance Measurements System Using RC Circuit

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Abstract

This article reports the technique of measuring capacitance using the concept of charging capacitors in the RC-series circuit. The proposed capacitance measuring system is built using 3 sub-systems: (1) Arduino M0 board (with 12-bit internal ADC) to control the process of discharging and charging capacitor voltages using the `digitalWrite()` function; (2) ERM20004FB-2 LCD with *I2C*-serial module to display measurement data; and (3) $R_{\text{CHARGE}}C_X$ -series circuit (R_{CHARGE} is a carbon-film 89.7 Mohm resistor and C_X is the capacitor to be measured). The charging time of the capacitor voltage from $0V_S$ to $0.5V_S(\Delta t)$ is calculated using the `analogRead()` and `micros()` functions. The C_X value is calculated using the equation $C_X = \frac{\Delta t}{(693.1471 \times R)} nF$ and with the value Δt displayed on the LCD module. The capacitance measuring system has been tested to measure capacitance of 14 ceramic-disk capacitors from $1nF$ to $100nF$ with an error rate $< \pm 0.7\%$ (compared to LCR-821). The results of the study concluded that the error rate was influenced by changes in the resistance value of R_{CHARGE} .

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1. Introduction

Microcontroller systems can be implemented to measure capacitance by using 3 ways: (1) using an RC or LC relaxation oscillator (R and L values are known), measuring the output frequency, and calculating capacitance using resonance frequency equations [1 – 3]; (2) using RC Monostable-MV (R value known), measure T_{ON} pulse width, and calculating capacitance using pulse width equation [4 – 5]; and (3) using a capacitor charging system in RC-series circuit with a stable DC voltage source, measuring the charging time until the capacitor voltage reaches a certain value, and calculating capacitance using the charging equation of the capacitor [6-9]. The accuracy of the capacitance measurement by measuring the charging time can be increased using Arduino M0 which has a 12-bit ADC [10].

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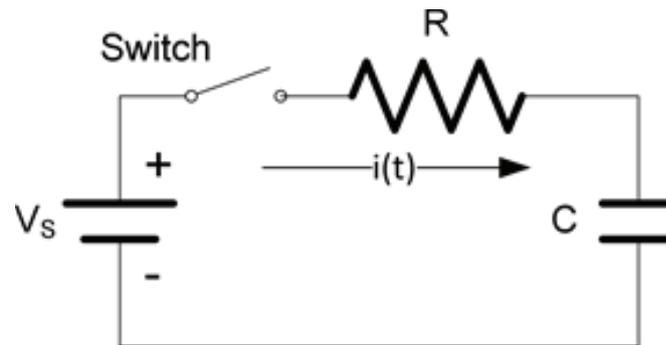


Figure 1: RC circuit with DC voltage source.

2. Methods and Equipment

2.1. Methods

2.1.1. RC charging circuit

The RC charging circuit is realized using a DC voltage source, resistor, and capacitor connected in series as shown in Figure 1 [11]. When the switch is closed, current $i(t)$ flows from the voltage source through resistors and capacitors so that equations (1) to (3).

$$V_S = V_R + V_C \quad (1)$$

$$V_S = i(t)R + \frac{1}{c} \int_{t=0}^{t=\sim} idt \quad (2)$$

$$i(t) = \frac{V_S}{R} e^{-\frac{t}{RC}} \quad (3)$$

The capacitor voltage can be calculated using equation (4). If the values of R , V_S , and Δt (the charging time of $V_C(t) = 0.5V_S$ to V_S) is known, then capacitance can be calculated using equations (5) to (7) [11].

$$V_c(r) = V_s (1 - e^{-\frac{r}{RC}}) \quad (4)$$

$$e^{-\frac{r}{RC}} = \frac{V_S - V_C(t)}{V_S} \quad (5)$$

$$-t = RC \ln \left(\frac{V_S - 0,5V_S}{V_S} \right) \quad (6)$$

$$C_X = \frac{\Delta t}{0,6931471 \times R_{CHG}} \text{Farad} \quad (7)$$

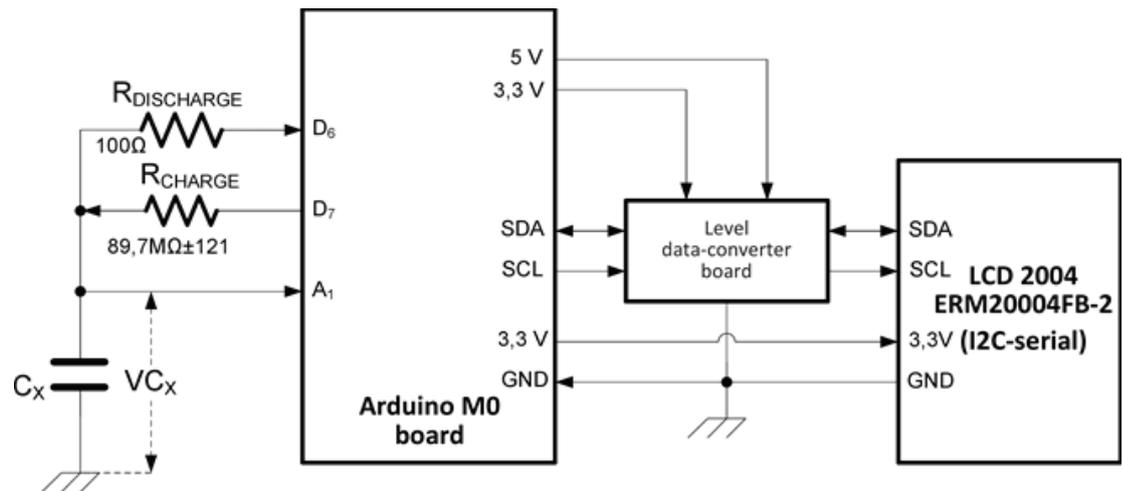


Figure 2: Capacitance measurement system circuit.

2.1.2. Description of the capacitance measurement system

The capacitance measuring system (Figure 2) was built using the concept of charging a capacitor C_X in an RC-series circuit that is controlled by Arduino M0 using pinMode() and digitalWrite(). Before the charging cycle, the C_X voltage is emptied through $R_{DISCHARGE}$ which is connected to the ground through a digital pin 6. C_X charging cycle is done through R_{CHARGE} which is connected to a voltage of 3.3 Volts via digital pin 7. C_X charging time from $0V_S$ to $0.5V_S(\Delta t)$ is calculated using the micros() function and then the capacitance can be calculated (equation 7) and displayed to the ERM20004FB-2 LCD with I2C-serial module. The pseudo-code of the Arduino M0-based capacitance measuring system uses the concept of charging capacitors in the RC-series circuit as described below:

1. discharging C_X until $V_{C_X} = 0$ Volts,
2. charging C_X and save time (t1),
3. stop charging when the ADC = 2048 ($V_{C_X} = 0.5V_S$),
4. save time (t2),
5. calculate Δt and C_X using equation 7,
6. show C_X and Δt values to LCD, and
7. repeat step 1.

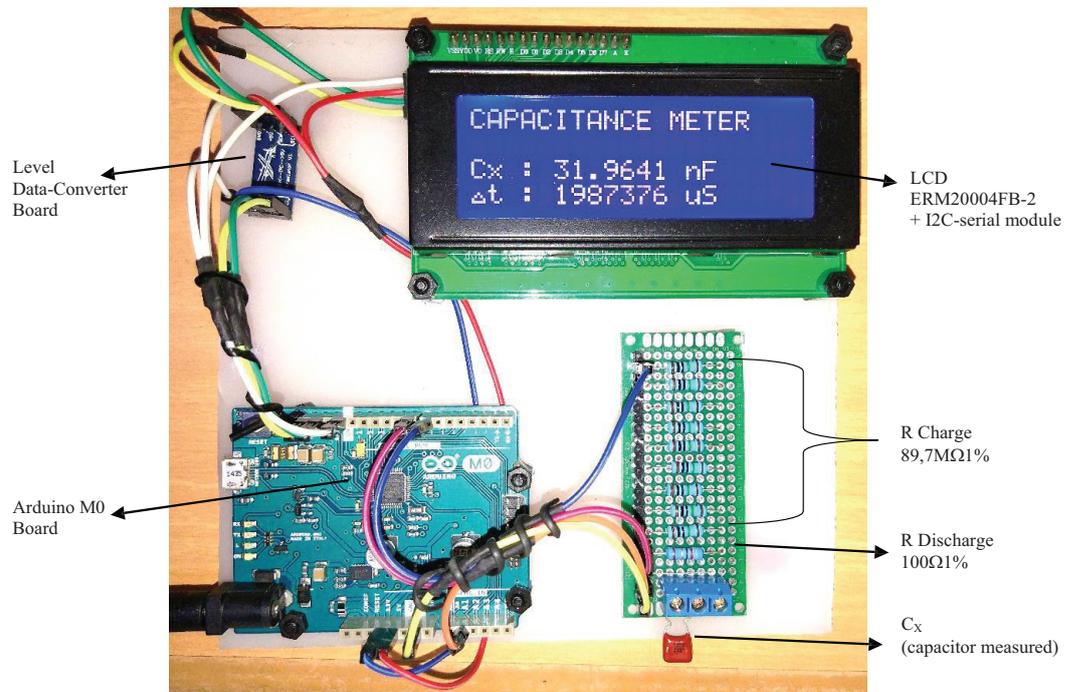


Figure 3: Capacitance measuring system when measuring C_x (323K or 32nF±5%).

3. Results

$R_{DISCHARGING}$ is set at 100Ω1% to get a fast discharge time ($t_{6RC} = 120\mu Sec$) when connected with C_x maximum (100nF) and $R_{CHARGING}$ determined at 89.7MΩ (9 resistors in series) to get Δt minimum $> 50000\mu S$ when connected to C_x minimum (1nF). Level data converter module (3.3Volt to 5Volt) is used to connect SDA and SCL signals from Arduino M0 to 4 × 20char LCD boards (with I2C-serial module). Capacitor measurement system has been successfully created (Figure 3, not calibrated, and has been tested to measure the capacitance of 14 ceramis-disks capacitors alternately using GWinstek LCR-821 (5 times each) and the results are shown in Table 1. Sketch of the system is created using Arduino IDE ver. 1.9.0-Beta and written in the following paragraph:

```

1 #include <LiquidCrystal_I2C.h>
2 LiquidCrystal_I2C lcd(0x27,20,4);
3 byte delta[]=
4 { B00000,B00000,B00000,B00100,B01010, B10001, B11111,B00000 };
5 unsigned long t1, t2, dt; float R, nanoF;
6 void setup()
7 { lcd.begin(); lcd.clear();
8   lcd.setCursor(0, 0); lcd.print("CAPACITANCE METER");
9   lcd.setCursor(0, 2); lcd.print("Cx : ");
10  lcd.createChar(0, delta); lcd.setCursor(0, 3); lcd.write(0);
11  lcd.setCursor(1, 3); lcd.print("t : ");
12  pinMode(7, OUTPUT); digitalWrite(7, LOW);
13  pinMode(8, OUTPUT); digitalWrite(8, LOW);
14  delay(5000);
15  analogReadResolution(12);
16  R = 89.7;
17 }

18 void loop()
19 { do { pinMode(8, OUTPUT);
20       digitalWrite(8, LOW);
21       delay(2000);
22     } while(analogRead(0) < 1);
23   pinMode(8, INPUT);
24   digitalWrite(7,HIGH);
25   t1 = micros();
26   while(analogRead(1) < 2048){} //ADC=2048 equal to 0,5VS
27   t2 = micros();
28   digitalWrite(7,LOW);
29   dt = t2 - t1;
30   nanoF = dt/(693.1471*R);
31   lcd.setCursor(5, 2); lcd.print(nanoF,4); lcd.print(" nF ");
32   lcd.setCursor(5, 3); lcd.print(dt); lcd.print(" uS ");
33 }

```

C_X measurement results (columns 2 and 4 in Table 1) are the average of 5 measurements using LCR- 821 and using capacitance measuring system. The % error (column 8) value is calculated using equation (8).

$$\%error = \frac{C_X \text{ system value} - C_X \text{ LCR-821}}{C_X \text{ LCR-821}} \times 100 \quad (8)$$

4. Discussion

Referring to equation (7), there are 2 variables that affect the measurement results of capacitance: (1) stability of the Δt ; and (2) stability of the R_{CHARGE} . Because Δt is generated from the function of `micros()` which has a $4\mu S$ resolution [12] so that it is assumed that it does not affect the measurement results, the change in the R_{CHG} value will cause a change in the value of the C_X measurement. If the R_{CHARGE} value rises, then the C_X measurement value will decrease and vice versa. The average

TABLE 1: Data from measurement of 14 capacitors.

| No. | capasitor (ceramics disk) value | measurement results | | | | | |
|-----|---------------------------------|---------------------|--------|------------------------------|--------|-------------------|---------------------|
| | | LCR-821 | | capacitance measuring system | | | % measurement error |
| | | C_x (nF) | SD | C_x (nF) | SD | $\Delta t(\mu S)$ | |
| 1 | 2 | 3 | 4 | 5 | 6 | 7 | 8 |
| 1 | 102K (10nF 10%) | 0,9208 | 0,0091 | 0,9271 | 0,0110 | 68,732 | 0,68 |
| 2 | 302M (3nF 20%) | 3,1005 | 0,0143 | 3,0948 | 0,0509 | 219,994 | -0,18 |
| 3 | 472K (4n7F 10%) | 4.4351 | 0,0016 | 4.4334 | 0,0859 | 229,528 | -0.04 |
| 4 | 103G (10nF 2%) | 9,4243 | 0,0018 | 9,4108 | 0,0058 | 567,639 | -0,14 |
| 5 | 103K (10nF 10%) | 9,7432 | 0,0068 | 9,7289 | 0,0109 | 586,508 | -0,15 |
| 6 | 153J (15nF 5%) | 15,4270 | 0,0083 | 15,4217 | 0,0377 | 899,649 | -0,03 |
| 7 | 223K (22nF 10%) | 20.7686 | 0,0103 | 20.6276 | 0,0392 | 1,266,618 | -0.68 |
| 8 | 273K (27nF 10%) | 25.9722 | 0,0181 | 25.7965 | 0,0241 | 1,590,332 | -0.68 |
| 9 | 333K (33nF 10%) | 31.9410 | 0,0113 | 31.9659 | 0,0796 | 1,984,776 | 0.08 |
| 10 | 473J (47nF 5%) | 41.9192 | 0,0274 | 41.8124 | 0,1494 | 2,598,063 | -0.25 |
| 11 | 563K (56nF 10%) | 52.7006 | 0,0576 | 52.6150 | 0,0948 | 3,255,986 | -0.16 |
| 12 | 633J (63nF 5%) | 69.0542 | 0,1407 | 68.8577 | 0,0623 | 4,272,470 | -0.28 |
| 13 | 104K(100nF 10%) | 94,3276 | 0,1942 | 94,4634 | 0,1975 | 5,891,775 | 0,14 |
| 14 | 104J(100nF 5%) | 98.5234 | 0,0575 | 98.5654 | 0,2419 | 6,128,104 | 0.04 |

R_{CHARGE} value is $89.7M\Omega$ with standard deviation 121 (measured 5 times using LCR-821), so it can be concluded that there is a correlation between the % error value of the measurement of the capacitance measuring system and the instability of the R_{CHARGE} value.

5. Conclusion

An Arduino-based capacitance measuring system uses the technique of calculating the charging time of the capacitor voltage in the RC-series circuit has been successfully made to measure the capacitance of 14 ceramic-disk capacitors with a measurement error rate $< \pm 0.7\%$ (compared to LCR-821).

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Conflict of Interest

The researcher does not have a conflict of interest related to the completion of this article.

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